HEXFET® Power MOSFET

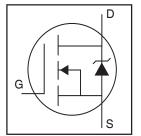


### **Features**

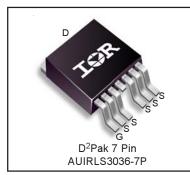
- Advanced Process Technology
- Ultra Low On-Resistance
- · Logic Level Gate Drive
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Timax
- Lead-Free, RoHS Compliant
- Automotive Qualified \*

### Description

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.



V <sub>DSS</sub>	60V
R <sub>DS(on)</sub> typ.	1.5m $\Omega$
max.	1.9m $\Omega$
I <sub>D (Silicon Limited)</sub>	300A①
I <sub>D (Package Limited)</sub>	240A



G	D	S
Gate	Drain	Source

Dana Bant Namelan	De de la Trace	Standard Pa	ck	Onderselle Best Nessel en	
Base Part Number	Package Type	Form	Quantity	Orderable Part Number	
		Tube	50	AUIRLS3036-7P	
AUIRLS3036-7P	D2Pak 7 Pin	Tape and Reel Left	800	AUIRLS3036-7TRL	
		Tape and Reel Right	800	AUIRLS3036-7TRR	

### **Absolute Maximum Ratings**

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (T<sub>A</sub>) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units	
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	300⊕		
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	210	٦ ,	
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Package Limited)	240	A	
I <sub>DM</sub>	Pulsed Drain Current ②	1000		
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	380	W	
	Linear Derating Factor	2.5	W/°C	
$V_{GS}$	Gate-to-Source Voltage	± 16	V	
E <sub>AS</sub>	Single Pulse Avalanche Energy (Thermally Limited) 3	300	mJ	
I <sub>AR</sub>	Avalanche Current ②	0 5 14 15 00 00		
E <sub>AR</sub>	Repetitive Avalanche Energy ©	See Fig. 14, 15, 22a, 22b	mJ	
dv/dt	Peak Diode Recovery ®	8.1	V/ns	
T <sub>J</sub> Operating Junction and		-55 to + 175		
T <sub>STG</sub>	Storage Temperature Range	-55 10 + 175	°C	
	Soldering Temperature, for 10 seconds (1.6mm from case)	300		

### **Thermal Resistance**

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case 9 ®		0.40	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount, steady state) ®		40	

HEXFET® is a registered trademark of International Rectifier.

<sup>\*</sup>Qualification standards can be found at http://www.irf.com/



## Static Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	60			V	$V_{GS} = 0V, I_{D} = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.059		V/°C	Reference to 25°C, I <sub>D</sub> = 5mA <sup>②</sup>
D	Static Drain-to-Source On-Resistance		1.5	1.9	0	V <sub>GS</sub> = 10V, I <sub>D</sub> = 180A ⑤
R <sub>DS(on)</sub>	Static Drain-to-Source Off-nesistance		1.7	2.2	mΩ	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 150A ⑤
$V_{GS(th)}$	Gate Threshold Voltage	1.0		2.5	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
gfs	Forward Transconductance	390			S	$V_{DS} = 10V, I_{D} = 180A$
R <sub>G(int)</sub>	Internal Gate Resistance		1.9		Ω	
I <sub>DSS</sub>	Drain-to-Source Leakage Current			20		$V_{DS} = 60V, V_{GS} = 0V$
				250	μA	$V_{DS} = 60V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			100	- A	V <sub>GS</sub> = 16V
	Gate-to-Source Reverse Leakage			-100	nA	V <sub>GS</sub> = -16V

### Dynamic Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$Q_g$	Total Gate Charge		110	160		I <sub>D</sub> = 180A
$Q_{gs}$	Gate-to-Source Charge		33			$V_{DS} = 30V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge		53		nC	V <sub>GS</sub> = 4.5V ⑤
Q <sub>sync</sub>	Total Gate Charge Sync. (Q <sub>g</sub> - Q <sub>gd</sub> )		57		Ī	$I_D = 180A, V_{DS} = 0V, V_{GS} = 4.5V$
t <sub>d(on)</sub>	Turn-On Delay Time		81			$V_{DD} = 39V$
t <sub>r</sub>	Rise Time		540		]	$I_D = 180A$
t <sub>d(off)</sub>	Turn-Off Delay Time		89		ns	$R_G = 2.1\Omega$
t <sub>f</sub>	Fall Time		170		Ī	V <sub>GS</sub> = 4.5V ⑤
C <sub>iss</sub>	Input Capacitance		11270			$V_{GS} = 0V$
C <sub>oss</sub>	Output Capacitance		1025		Ī	$V_{DS} = 50V$
C <sub>rss</sub>	Reverse Transfer Capacitance		520		pF	f = 1.0MHz
C <sub>oss</sub> eff. (ER)	Effective Output Capacitance (Energy Related)		1460		Ī	$V_{GS} = 0V$ , $V_{DS} = 0V$ to 48V $\odot$
C <sub>oss</sub> eff. (TR)	Effective Output Capacitance (Time Related) ©		1630		]	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 0V to 48V ©

### **Diode Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			300		MOSFET symbol
	(Body Diode)			300	_ \	showing the
I <sub>SM</sub>	Pulsed Source Current			1000	A	integral reverse
	(Body Diode) ③			1000		p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 180A, V_{GS} = 0V $ (5)
t <sub>rr</sub>	Reverse Recovery Time		57			$T_J = 25^{\circ}C$ $V_R = 51V$ ,
			60		ns	$T_J = 125^{\circ}C$ $I_F = 180A$
Q <sub>rr</sub>	Reverse Recovery Charge		140			$T_J = 25^{\circ}C$ di/dt = 100A/ $\mu$ s $\odot$
			160			$T_J = 125^{\circ}C$
I <sub>RRM</sub>	Reverse Recovery Current		4.6		Α	$T_J = 25^{\circ}C$
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

### Notes:

- ① Calcuted continuous current based on maximum allowable junction temperature Bond wire current limit is 195A. Note that current limitation arising from heating of the device leds may occur with some lead mounting arrangements.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ Limited by  $T_{Jmax}$ , starting  $T_J = 25^{\circ}C$ , L = 0.018mH  $R_G = 25\Omega$ ,  $I_{AS} = 180A$ ,  $V_{GS} = 10V$ . Part not recommended for use above this value .
- ④  $I_{SD} \le 180A$ , di/dt ≤ 1070A/µs,  $V_{DD} \le V_{(BR)DSS}$ ,  $T_{J} \le 175$ °C.

- ⑤ Pulse width  $\leq 400 \mu s$ ; duty cycle  $\leq 2\%$ .
- $^{\circ}$  C  $_{\rm oss}$  eff. (TR) is a fixed capacitance that gives the same charging time as C  $_{\rm oss}$  while V  $_{\rm DS}$  is rising from 0 to 80% V  $_{\rm DSS}$ .
- $\odot$  C<sub>oss</sub> eff. (ER) is a fixed capacitance that gives the same energy as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 to 80% V<sub>DSS</sub>.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniquea refer to application note # AN- 994 echniques refer to application note #AN-994.
- $^{\circ}$  R<sub> $\theta$ JC</sub> value shown is at time zero.



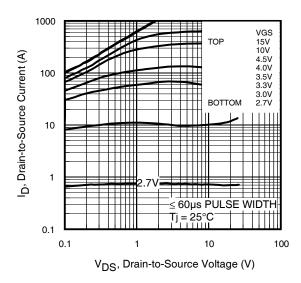


Fig 1. Typical Output Characteristics

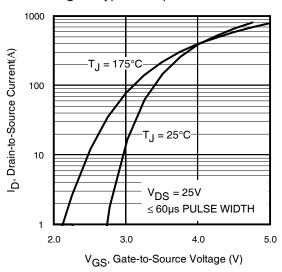


Fig 3. Typical Transfer Characteristics

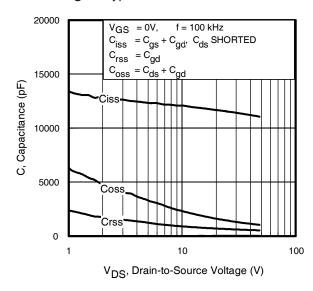


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

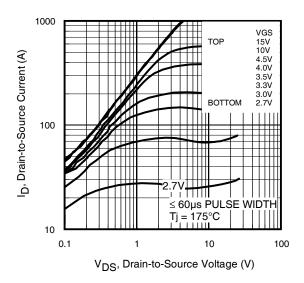


Fig 2. Typical Output Characteristics

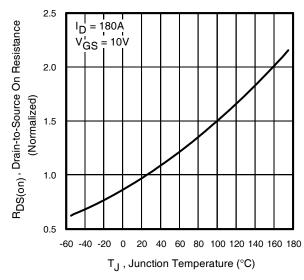


Fig 4. Normalized On-Resistance vs. Temperature

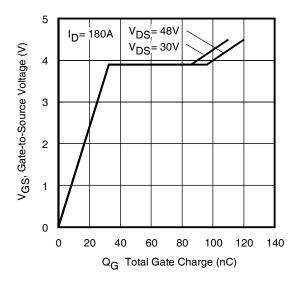
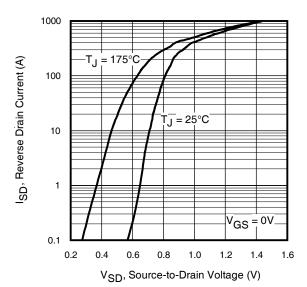
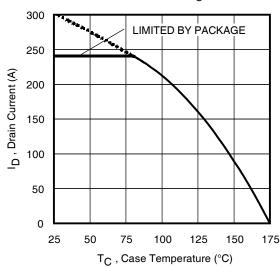


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage





**Fig 7.** Typical Source-Drain Diode Forward Voltage



**Fig 9.** Maximum Drain Current vs. Case Temperature

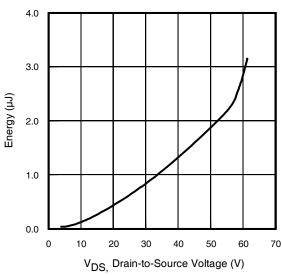


Fig 11. Typical C<sub>OSS</sub> Stored Energy

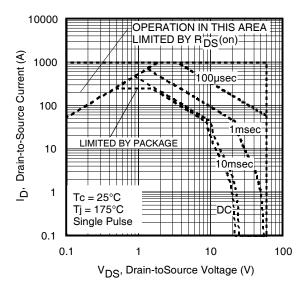


Fig 8. Maximum Safe Operating Area

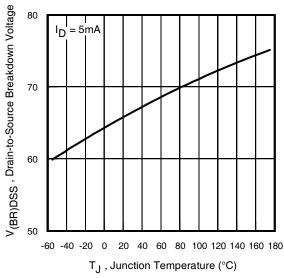


Fig 10. Drain-to-Source Breakdown Voltage

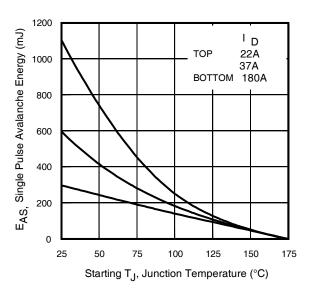


Fig 12. Maximum Avalanche Energy Vs. DrainCurrent



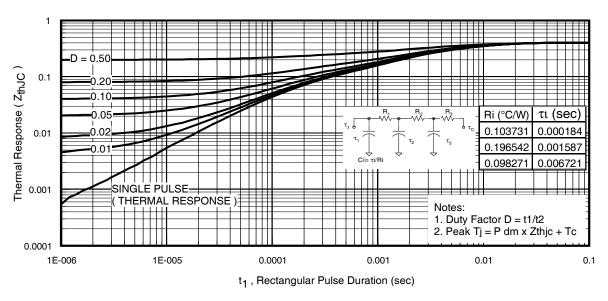


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

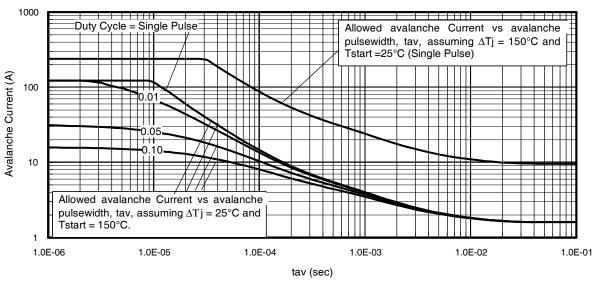


Fig 14. Typical Avalanche Current vs. Pulsewidth

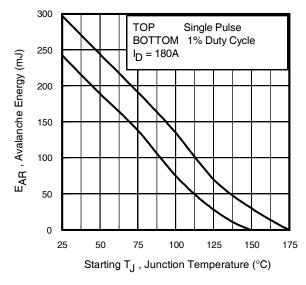


Fig 15. Maximum Avalanche Energy vs. Temperature

### Notes on Repetitive Avalanche Curves , Figures 14, 15: (For further info, see AN-1005 at www.irf.com)

- 1. Avalanche failures assumption:
- Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{jmax}$ . This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as T<sub>imax</sub> is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 22a, 22b.
- 4.  $P_{D (ave)}$  = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I<sub>av</sub> = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 14, 15).
- tav = Average time in avalanche.

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- D = Duty cycle in avalanche =  $t_{av} \cdot f$
- $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see Figures 13)

 $P_{D \; (ave)}$  = 1/2 ( 1.3·BV·I $_{av})$  =  $\triangle T / \; Z_{thJC}$  $I_{av} = 2\triangle T/ [1.3 \text{ BV-}Z_{th}]$ E<sub>AS (AR)</sub> = P<sub>D (ave)</sub>·t<sub>av</sub>

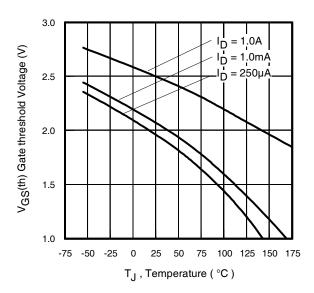


Fig 16. Threshold Voltage Vs. Temperature

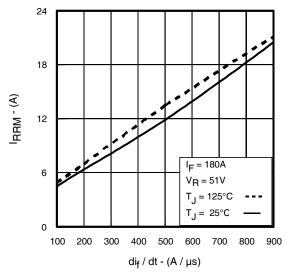


Fig. 18 - Typical Recovery Current vs. dif/dt

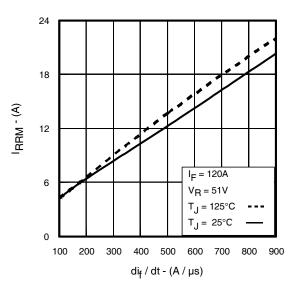


Fig. 17 - Typical Recovery Current vs. di<sub>f</sub>/dt

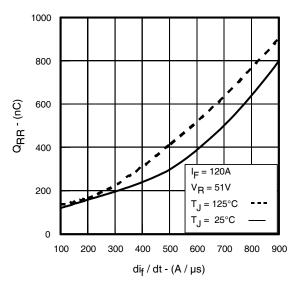


Fig. 19 - Typical Stored Charge vs. di<sub>f</sub>/dt

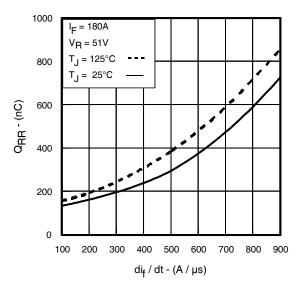


Fig. 20 - Typical Stored Charge vs. dif/dt



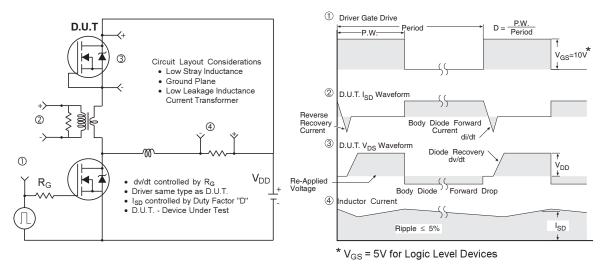


Fig 21. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

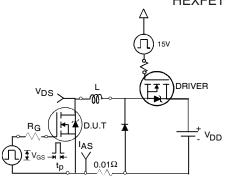


Fig 22a. Unclamped Inductive Test Circuit

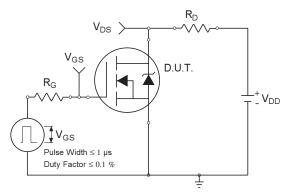


Fig 23a. Switching Time Test Circuit

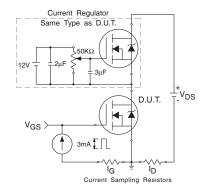


Fig 24a. Gate Charge Test Circuit

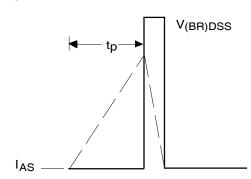


Fig 22b. Unclamped Inductive Waveforms

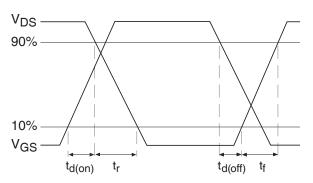


Fig 23b. Switching Time Waveforms

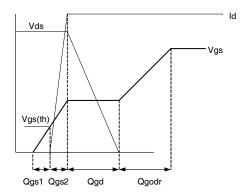


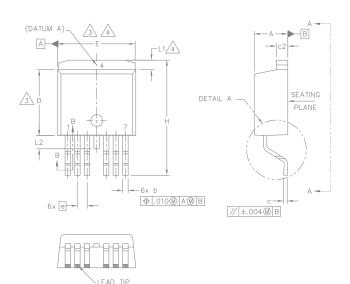
Fig 24b. Gate Charge Waveform

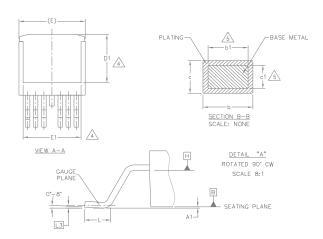
April 03, 2014



# D<sup>2</sup>Pak - 7 Pin Package Outline

Dimensions are shown in millimeters (inches)





S		DIMEN	ISIONS		N
M B O	MILLIM	ETERS	ERS INCHE		N O T E S
L	MIN.	MAX.	MIN.	MAX.	S
А	4.06	4.83	.160	.190	
A1	_	0.254	_	.010	
b	0.51	0.99	.020	.036	
b1	0.51	0.89	.020	.032	5
С	0.38	0,74	.015	.029	
с1	0.38	0.58	.015	.023	5
c2	1.14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	7.42	.270	.292	4
E	9.65	10.54	.380	.415	3,4
E1	6.22	8.48	.245	.334	4
е	1.27	BSC	.050	BSC	
Н	14.61	15.88	.575	.625	
L	1.78	2.79	.070	.110	
L1	_	1.68	_	.066	4
L2	_	1.78	_	.070	
L3	0.25	BSC	.010	BSC	

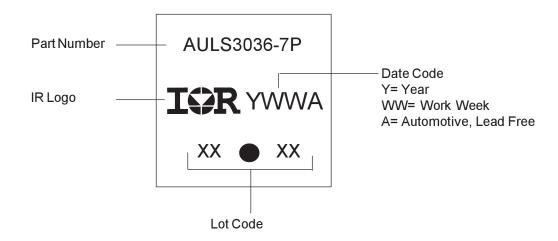
#### NOTES

- 1. DIMENSIONING AND TOLERANCING AS PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
- 4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
- 5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.
- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263CB. EXCEPT FOR DIMS. E, E1 & D1.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



## D<sup>2</sup>Pak - 7 Pin Part Marking Information



## D<sup>2</sup>Pak - 7 Pin Tape and Reel

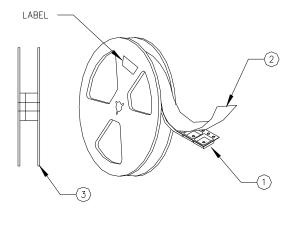
NOTES, TAPE & REEL, LABELLING:

- 1. TAPE AND REEL.
  - 1,1 REEL SIZE 13 INCH DIAMETER.
  - 1.2 EACH REEL CONTAINING 800 DEVICES.
  - 1.3 THERE SHALL BE A MINIMUM OF 42 SEALED POCKETS CONTAINED IN THE LEADER AND A MINIMUM OF 15 SEALED POCKETS IN THE TRAILER.
  - 1.4 PEEL STRENGTH MUST CONFORM TO THE SPEC. NO.
  - 1.5 PART ORIENTATION SHALL BE AS SHOWN BELOW.
  - 1.6 REEL MAY CONTAIN A MAXIMUM OF TWO UNIQUE LOT CODE/DATE CODE COMBINATIONS. REWORKED REELS MAY CONTAIN A MAXIMUM OF THREE UNIQUE LOT CODE/DATE CODE COMBINATIONS. HOWEVER, THE LOT CODES AND DATE CODES WITH THEIR RESPECTIVE QUANTITIES SHALL APPEAR ON THE BAR CODE LABEL FOR THE AFFECTED REEL.

- 2. LABELLING (REEL AND SHIPPING BAG).
  - 2.1 CUST. PART NUMBER (BAR CODE): IRFXXXXSTRL-7P
  - 2.2 CUST. PART NUMBER (TEXT CODE): IRFXXXXSTRL-7P
  - 2.3 I.R. PART NUMBER: IRFXXXXSTRL-7P
  - 2.4 QUANTITY:
  - 2.5 VENDOR CODE; IR

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- 2.6 LOT CODE:
- 2.7 DATE CODE:



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



# **Qualification Information**<sup>†</sup>

		Automotive			
		(per AEC-Q101) <sup>††</sup>			
Qualification Le	evel	Comments: This part number(s) passed Automot qualification. IR's Industrial and Consumer qualification le is granted by extension of the higher Automotive level.			
Moisture Sensit	ivity Level	D <sup>2</sup> Pak 7 Pin MSL1			
	Machine Model	Class M4 (+/- 800V) <sup>†††</sup>			
		AEC-Q101-002			
	Human Body Model	Class H3A (+/- 6000V) <sup>†††</sup>			
ESD		AEC-Q101-001			
	Charged Device Model	Class C5 (+/- 2000V) <sup>†††</sup>			
		AEC-Q101-005			
RoHS Compliant		Yes			

<sup>†</sup> Qualification standards can be found at International Rectifier's web site: <a href="http://www.irf.com/">http://www.irf.com/</a>

<sup>††</sup> Exceptions (if any) to AEC-Q101 requirements are noted in the qualification report.

<sup>†††</sup> Highest passing voltage.



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For technical support, please contact IR's Technical Assistance Center http://www.irf.com/technical-info/

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## **Revision History**

Date	Comments				
	Added "Logic Level Gate Drive" bullet in the features section on page 1				
4/2/2014	Updated part marking on page 8				
	• Updated typo on the fig.19 and fig.20, unit of y-axis from "A" to "nC" on page 6.				
	Updated data sheet with new IR corporate template				